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(54) Title: METHOD OF ANALYSING A STACK OF FLAT OBJECTS

(57) Abstract: The present invention relates to a method of analysing a stack of flat objects, which method comprises the steps of providing a stack of flat objects, which stack comprises at least one surface defined by the edges of flat objects, illuminating the surface of said stack, providing a two-dimensional image of the stack by making use of an optical sensor, and providing an output signal that represents the result of the analysis, wherein the provision of the two-dimensional image is carried out in such a manner that the image is enlarged in the y-direction and reduced in the x-direction, which y-direction is defined as the height of stack of flat objects and which x-direction is defined as the width of the stack of flat objects.